Enhanced and high temperature ACTT power switch

7 September 2018 Product data sheet

1. General description

Planar passivated AC Thyristor Triac power switch in a SOT186A (TO-220F) "full pack" plastic package with self-protective capabilities against low and high energy transients. This "series CTN" triac will commutate the full RMS current at the maximum rated junction temperature ($T_{j(max)}$ = 150 °C) without the aid of a snubber. It is used in applications where "high junction operating temperature capability" is required.

2. Features and benefits

- · Clamping structure ensuring safe high over-voltage withstand capability
- High junction operating temperature capability (T_{i(max)} = 150 °C)
- High minimum I_{GT} for guaranteed immunity to gate noise
- Full cycle AC conduction
- Isolated mounting base package
- Over-voltage withstand capability to IEC 61000-4-5
- Pin compatible with standard triacs
- Protective self turn-on capability for high energy transients
- Safe clamping capability for low energy over-voltage transients
- Less sensitive gate for high noise immunity
- Triggering in three quadrants only
- · Planar passivated for voltage ruggedness and reliability
- High commutation capability with maximum false trigger immunity
- Very high immunity to false turn-on by dV/dt and IEC 61000-4-4 fast transient
- Package meets UL94V0 flammability requirement
- Package is RoHS compliant
- Package meets UL1557 isolation test requirement rated at 2500V RMS

3. Applications

- AC fan, pump and compressor controls
- Highly inductive, resistive and safety loads
- Large and small appliances (White Goods)
- Reversing induction motor controls
- Applications subject to high temperature (T_{j(max)} = 150 °C)

4. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------|---------------------------------------|------------|-----|-----|-----|------|
| V_{DRM} | repetitive peak off- state voltage | | - | - | 800 | V |

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|--|---|------|-----|-----|------|
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_h \le 106 ^{\circ}\text{C}$; Fig. 2; Fig. 3 | - | - | 8 | А |
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5 | - | - | 80 | Α |
| | | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms | - | - | 88 | Α |
| Tj | junction temperature | | - | - | 150 | °C |
| V_{PP} | peak pulse voltage | T _j = 25 °C; non-repetitive, off-state; Fig. 6 | - | - | 2 | kV |
| Static chara | acteristics | | ' | | | |
| I _{GT} | gate trigger current | $V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G+;}$ $T_j = 25 \text{ °C; Fig. 8}$ | 5 | - | 35 | mA |
| | | $V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; } Fig. 8$ | 5 | - | 35 | mA |
| | | $V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$ | 5 | - | 35 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 10</u> | - | - | 40 | mA |
| V _T | on-state voltage | I _T = 10 A; T _j = 25 °C; <u>Fig. 11</u> | - | - | 1.5 | V |
| V _{CL} | clamping voltage | I_{CL} = 0.1 mA; t_p = 1 ms; T_j = 25 °C | 850 | - | - | V |
| Dynamic ch | naracteristics | | | | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 4000 | - | - | V/µs |
| | | V _{DM} = 536 V; T _j = 150 °C; exponential waveform; gate open circuit | 2000 | - | - | V/µs |
| dl _{com} /dt | rate of change of commutating current | V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 8 A; dV_{com}/dt = 20 V/ μ s; gate open circuit; snubberless condition | 12 | - | - | A/ms |
| | | V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 8 A; dV_{com}/dt = 10 V/ μ s; gate open circuit | 15 | - | - | A/ms |
| | | $V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 8 \text{ A};$ $dV_{com}/dt = 1 \text{ V/}\mu\text{s}; gate open circuit}$ | 20 | - | - | A/ms |

5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-------------------------|----------------------------|-----------------|
| 1 | СМ | common | mb | LР |
| 2 | LD | load | | |
| 3 | G | gate | | G—/ |
| mb | n.c. | mounting base; isolated | 1 2 3 TO-220F (SOT186A) | CM 003aaf296 |

6. Ordering information

Table 3. Ordering information

| Type number | | Package | | | | |
|-------------|---------------|---------|---|---------|--|--|
| | | Name | Description | Version | | |
| | ACTT8X-800CTN | TO-220F | plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 "full pack" | SOT186A | | |

7. Limiting values

Table 4. Limiting values
In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---------------------|--|---|-----|-----|------|
| V_{DRM} | repetitive peak off-state voltage | | - | 800 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_h \le 106$ °C; $Fig. 1$; $Fig. 2$; $Fig. 3$ | - | 8 | Α |
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5 | - | 80 | Α |
| | | full sine wave; T _{j(init)} = 25 °C; t _p = 16.7 ms | - | 88 | Α |
| l ² t | I ² t for fusing | t _p = 10 ms; sine-wave pulse | - | 32 | A²s |
| dl _T /dt | rate of rise of on-state current | I _G = 70 mA | - | 100 | A/µs |
| I _{GM} | peak gate current | | - | 2 | Α |
| P_{GM} | peak gate power | | - | 5 | W |
| P _{G(AV)} | average gate power | over any 20 ms period | - | 0.5 | W |
| T _{stg} | storage temperature | | -40 | 150 | °C |
| T _j | junction temperature | | - | 150 | °C |
| V_{PP} | peak pulse voltage | T _i = 25 °C; non-repetitive, off-state; Fig. 6 | - | 2 | kV |

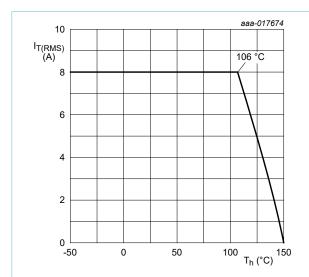


Fig. 1. RMS on-state current as a function of heatsink temperature; maximum values

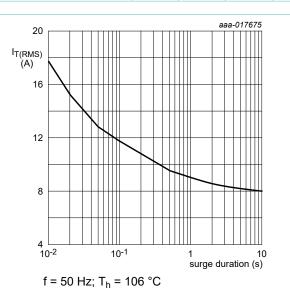


Fig. 2. RMS on-state current as a function of surge duration; maximum values

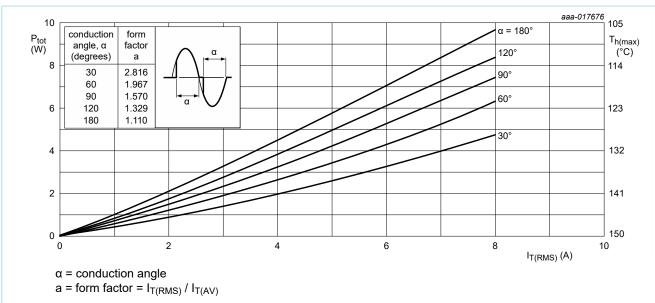


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

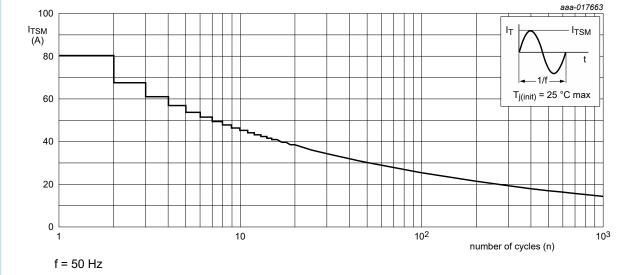


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

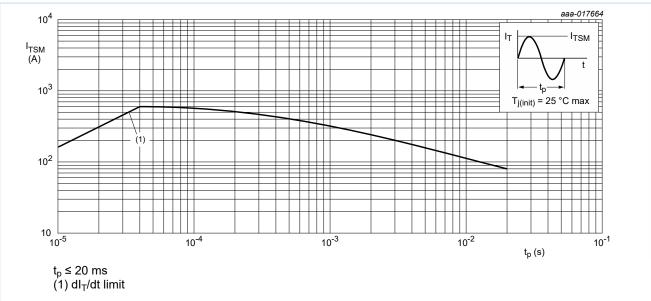


Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

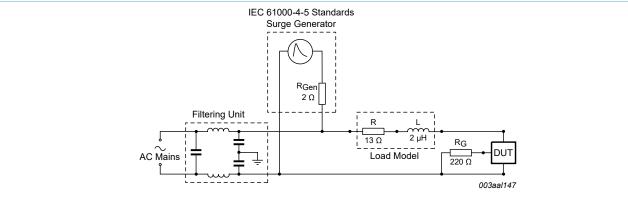


Fig. 6. Test circuit for inductive and resistive loads with conditions equivalent to IEC 61000-4-5

8. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|----------------------|--|--|-----|-----|-----|------|
| R _{th(j-h)} | thermal resistance from junction to | full or half cycle; with heatsink compound; Fig. 7 | - | - | 4.5 | K/W |
| | heatsink | full or half cycle; without heatsink compound | - | - | 6.5 | K/W |
| R _{th(j-a)} | thermal resistance from junction to ambient free air | in free air | - | 55 | - | K/W |

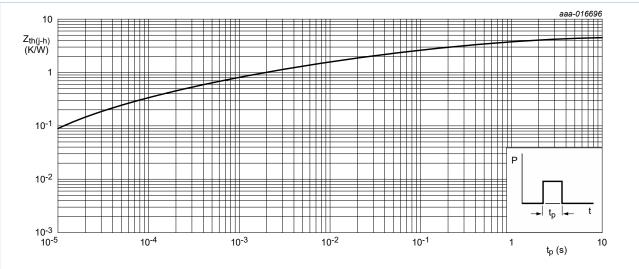


Fig. 7. Transient thermal impedance from junction to heatsink as a function of pulse duration

9. Isolation characteristics

Table 6. Isolation characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|------------------------|-----------------------|--|-----|-----|------|------|
| V _{isol(RMS)} | RMS isolation voltage | from all terminals to external heatsink; sinusoidal waveform; clean and dust free; $50 \text{ Hz} \le f \le 60 \text{ Hz}$; $T_h = 25 ^{\circ}\text{C}$ | - | - | 2500 | V |
| C _{isol} | isolation capacitance | from main terminal 2 to external heatsink; f = 1 MHz; T _h = 25 °C | - | 10 | - | pF |

10. Characteristics

Table 7. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|------|------|-----|------|
| Static char | acteristics | | , | | | , |
| I _{GT} ! | gate trigger current | $V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G+;}$ $T_j = 25 \text{ °C; } Fig. 8$ | 5 | - | 35 | mA |
| | | $V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; } Fig. 8$ | 5 | - | 35 | mA |
| | | $V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$ | 5 | - | 35 | mA |
| l _L | latching current | $V_D = 12 \text{ V}; I_G = 100 \text{ mA}; LD+ G+;$ $T_j = 25 \text{ °C}; Fig. 9$ | - | - | 50 | mA |
| | | $V_D = 12 \text{ V; } I_G = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; Fig. 9}$ | - | - | 60 | mA |
| | | $V_D = 12 \text{ V; } I_G = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } Fig. 9$ | - | - | 50 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 10</u> | - | - | 40 | mA |
| V _T | on-state voltage | I _T = 10 A; T _j = 25 °C; <u>Fig. 11</u> | - | - | 1.5 | V |
| V _{GT} | gate trigger voltage | $V_D = 12 \text{ V}; I_T = 100 \text{ mA}; T_j = 25 ^{\circ}\text{C};$ Fig. 12 | - | 0.8 | 1 | V |
| | | V _D = 400 V; I _T = 100 mA; T _j = 150 °C; Fig. 12 | 0.2 | 0.45 | - | V |
| I _D | off-state current | V _D = 800 V; T _j = 25 °C | - | - | 10 | μA |
| | | V _D = 800 V; T _j = 150 °C | - | - | 2 | mA |
| V _{CL} | clamping voltage | I _{CL} = 0.1 mA; t _p = 1 ms; T _j = 25 °C | 850 | - | - | V |
| Dynamic cl | naracteristics | | | | ' | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 4000 | - | - | V/µs |
| | | V _{DM} = 536 V; T _j = 150 °C; exponential waveform; gate open circuit | 2000 | - | - | V/µs |
| dI _{com} /dt | rate of change of commutating current | V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 8 A; dV_{com}/dt = 20 V/µs; gate open circuit; snubberless condition | 12 | - | - | A/ms |
| | | V_D = 400 V; T_j = 150 °C; $I_{T(RMS)}$ = 8 A; dV_{com}/dt = 10 V/µs; gate open circuit | 15 | - | - | A/ms |
| | | $V_D = 400 \text{ V}; T_j = 150 ^{\circ}\text{C}; I_{T(RMS)} = 8 \text{ A};$ $dV_{com}/dt = 1 \text{ V/}\mu\text{s}; gate open circuit}$ | 20 | - | - | A/ms |

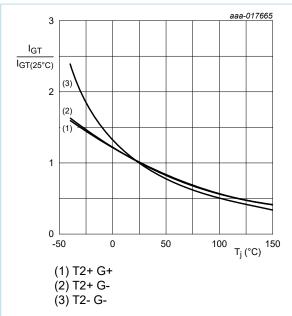


Fig. 8. Normalized gate trigger current as a function of junction temperature

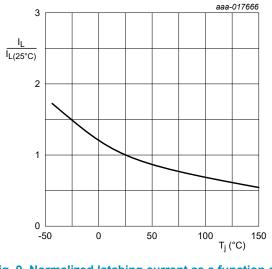


Fig. 9. Normalized latching current as a function of junction temperature

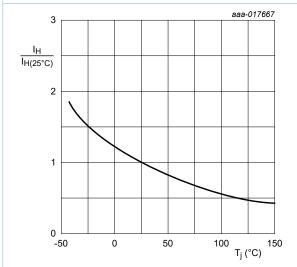
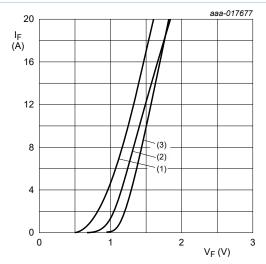


Fig. 10. Normalized holding current as a function of junction temperature



 V_o = 1.123 V; R_s = 0.025 Ω (1) T_j = 150 °C; typical values (2) T_j = 150 °C; maximum values (3) T_j = 25 °C; maximum values

Fig. 11. On-state current as a function of on-state voltage

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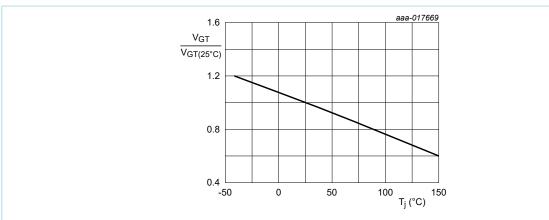


Fig. 12. Normalized gate trigger voltage as a function of junction temperature

11. Package outline

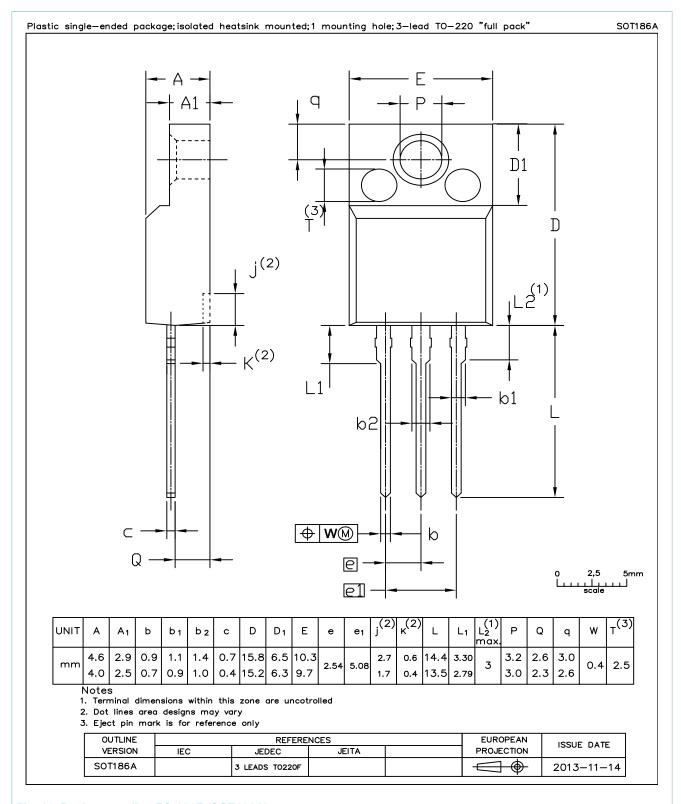


Fig. 13. Package outline TO-220F (SOT186A)

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|--------------------------------------|--------------------|---|
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